

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: MICHAELSEN, Carsten et al. ) Examiner:  
Application No.: unknown ) unknown  
Filing Date: unknown ) Art Unit:  
For: REFLECTOR FOR X-RAY RADIATION ) unknown

Atty. Docket No.: P8073US

Commissioner for Patents  
Alexandria, VA 22313-1450

U.S.A.

**INFORMATION DISCLOSURE STATEMENT**

The Examiner is referred to the List of Prior Art (Form PTO-1449A).

DE 44 07 278 is described on pages 1 and 2 of the instant specification,  
Handbuch der Physik on page 17, DE 197 01 419 on page 22, and  
DE 199 35 513 on page 29.

*Paul Vincent*

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Dr. Paul Vincent  
Reg. No. 37,461

Kohler Schmid & Partner  
Patentanwälte  
Ruppmannstrasse 27  
D-70565 Stuttgart  
Germany  
Telephone: 49-711-78 47 30  
Fax : 49-711-78 00 996

Enclosures:

PTO-Form 1449 (2 pages)  
Copies of cited references

Substitute for form 1449A/PTO		<u>Complete if Known</u>	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>		Application Number	
(Use as many sheets as necessary)		Filing Date	
		First Named Inventor	MICHAELSEN, Carsten et al.
		Group Art Unit	
		Examiner Name	
Sheet	1	of	2
Attorney Docket Number			P8073US

<b>Examiner Signature</b>		<b>Date Considered</b>	
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**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

**Complete if Known**

Application Number	
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Group Art Unit	
Examiner Name	

Sheet

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Attorney Docket Number

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**OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS**

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s). publisher, city and/or country where published	T
		M. Schuster et al., "Laterally Graded Multilayer Optics for X-Ray Analysis", SPIE, Denver, 199, p. 183 ff	
		M. Montel et al., "X-Ray Microscopy and Micro Radiography, Academic Press, New York, 1957, p. 177-185	
		V.E. Cosslett et al., "X-Ray Microscopy", Cambridge Press, 1960, p. 180 ff	
		S. Fluegge, "Handbuch der Physik", Vol. XXX, Springer Verlag, Berlin, 1957, p. 325 ff	

Examiner Signature	Date Considered